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(54) **Method of optical recognition and classification of pattern.**

(57) 1. An optical method of recognition and classification of patterns or image, on real time basis, comprising

(a) measuring necessary times a respective output of correlation between each of reference patterns and a specific pattern to be tested which is to belong to a specific class;

(b) calculating a representative value for each set of the correlation output, from the set of the measured data of the correlation outputs, in regard to said each of reference patterns and said specific pattern, and a respective parameter to represent the degree of the deviation of the measured data of said correlation outputs belonging to said each set of correlation outputs;

(c) making a respective membership function corresponding to each of said reference patterns for each of the specific classes to which the specific pattern should be classified or belong, on the basis of said respective representative value and said respective parameter;

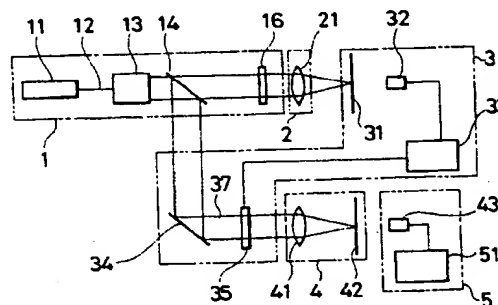
(d) estimating a respective membership value to each of the respective membership function, assigned to each of the specific classes to which the pattern should be classified or belong, on the basis of the respective output of correlation between the pattern to be tested and said each of reference patterns;

(e) selecting the smallest membership value among the resulting membership values;
or estimating an average of all said resulting membership values;

(f) using the resulting smallest membership

value or the resulting average as a degree to judge how much said pattern to be tested belongs to each of the specific classes.

FIG. 1



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BACKGROUND OF THE INVENTION

Field of the Invention

The present invention relates to a method of recognition and classification of patterns or image, to be utilized in the field of optical data processing, on a real-time basis. This invention relates to a method of recognition and classification of patterns to be used particularly for processing of data and information such as associative recognition processing, classification processing in the field of optical measurement and image processing.

Description of the Prior Art

There have been proposed a matched filter method and a joint transformation method as an optical estimation for correlation of patterns.

The matched filter method comprises firstly Fourier transforming two-dimensionally each of the reference patterns, irradiating each of the reference patterns with a light beam to produce a so called "Fourier transformation hologram" to be used as a filter, and superposing the Fourier transformation of the pattern to be reviewed on the hologram filter so as to process correlation of the patterns.

The joint transformation method comprises recording a joint Fourier transformation pattern resulting from the pattern to be reviewed and each of the reference patterns, and irradiating the resulting recorded pattern with a plane wave beam, so as to process correlation of the patterns.

Both of the above methods provides the reference patterns in such number that the number of the reference patterns in group is ready in correspondence to the number of the patterns to be recognized and classified, and provides a detection result which has been obtained from the presentation of the pattern to be reviewed on the basis of the pattern having maximum correlation output, i.e. the auto-correlation output, and therefore, the number of the reference patterns to be stored will be increased with increase of the number of the reference patterns to be reviewed. As a result, the loading of a two-dimensional or three-dimensional spatial photo modulator will be raised, and accordingly, the ability of the recognition-classification apparatus will be much limited by the ability of the spatial light modulator. Therefore, it is difficult to provide a practical and efficient apparatus for optically recognition and classification of the patterns.

The inventors have invented a method of improving the efficiency of recognition and association of the pattern, even with the increased number of the reference patterns, in which the light intensity of irradiation to the reference patterns is changed or adjusted by feed-backing on the basis of the correlation which has been obtained by the said joint Fourier transfor-

mation method. However, it has been desired that the number of the patterns to be reviewed in parallel should be raised in practice.

Summary of the Invention

Accordingly, an object of the present invention is improved optical method of recognition and classification wherein the necessary number of the reference patterns to be recorded can be significantly small, and many patterns can be recognized and classified in parallel.

It is another object of the present invention to provide an optical method of recognition and classification on real time basis.

BRIEF DESCRIPTION OF THE DRAWINGS

The objects and features of the present invention will become more apparent from the consideration of the following detailed description taken in conjunction with the accompanying drawings in which:

FIG. 1 shows generally a structure of a typical joint Fourier transformation optical system to be used for a optical correlation processing system.

FIG. 2 shows schematically one pattern to be reviewed and a set of reference patterns displayed on the plane of a display device, wherein the joint Fourier transformation correlator.

FIG. 3 shows a schematic view of displayed correlation outputs displayed on a display device, wherein the joint Fourier transformation correlator.

FIG. 4 shows a schematic illustration showing membership functions produced on the basis of the respective correlation output resulting from each of the reference patterns "V" and "E" with one pattern to be reviewed in accordance with the inventive method of recognition and classification of the pattern, wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 5 is a graph showing the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns "V" and "E" with the other pattern to be reviewed in accordance with the inventive method of recognition and classification of the pattern, wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 6 shows a graph showing the relation of the membership functions produced on the basis of the respective correlation of each of the reference pat-

terns "V" and "E" with another pattern to be reviewed in accordance with the inventive method of recognition and classification of the pattern, wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 7 shows a table showing schematically the membership values with regard to the measured correlation of each of the reference patterns "E" and "V" with unknown pattern in accordance with the inventive method of recognition and classification of the pattern.

FIG. 8 shows schematically how to gain the patterns of the mutual correlation resulting from the reference patterns "E" and "H", to be used for recognition and classification of pattern in accordance with the present invention.

FIG. 9 shows 15 graphs showing the relation of the membership functions produced on the basis of the respective correlation of each of the patterns (A, E, H, N, T, L, O, I, K, M, V, W, X, Y and Z) to be reviewed, with the two reference patterns (E, V) in accordance with the inventive method of recognition and classification of the pattern, wherein a solid line indicates a membership function prepared on the basis of the correlation with a reference pattern "E", and a dotted curve indicates a membership function prepared on the basis of the correlation with a reference pattern "V".

FIG. 10 is a table showing the recognition result with regard to the unknown patterns, as produced by using an experimentally obtained AND calculation method in accordance with the present invention, and the probability of the recognition result.

FIG. 11 shows schematically the structure of one of the optical correlation processing apparatus using matched filtering in accordance with the inventive optical method of recognition and classification.

FIG. 12 shows a schematic illustration of an optical system of the other type of the optical correlation processing apparatus to be used for the inventive optical method of recognition and classification.

FIG. 13 shows schematically one pattern (H) to be reviewed and reference patterns (E, V, X) in case which the jointed Fourier transformation correlator is used for recognition and classification of pattern.

FIG. 14 shows schematically the respective cross correlations of one pattern to be reviewed and the reference patterns as shown in FIG. 13, in case which the jointed Fourier transformation optical device is used for recognition and classification of pattern.

FIG. 15 shows a graph showing schematically the relation of the membership functions produced on the basis of the respective correlation output of each of the reference patterns (V, X, E) with one pattern (H)

to be reviewed in accordance with the inventive method of recognition and classification of the pattern, wherein the dotted curve for "E" indicated a membership function prepared on the basis of the correlation with a reference pattern "E", and further wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 16 is a graph showing the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns (V, X, E) with another pattern to be reviewed in accordance with the inventive method of recognition and classification of the pattern, and further wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 17 is a graph showing the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns (V, X, E) with the other pattern to be reviewed in accordance with the inventive method of recognition and classification of the pattern, and further wherein "a" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "E", and "b" indicates the position corresponding to the correlation output resulting from one pattern to be reviewed and a reference pattern "V".

FIG. 18 shows a table showing a calculated overlap area of the membership functions, resulting from the pair of pattern to be reviewed, and each of the reference patterns "E", "V" and "X", in order to select an appropriate pair with one of the reference patterns, in accordance with the inventive method of recognition and classification of the pattern.

FIG. 19 shows a table showing a calculated maximum membership values, resulting from the pair of pattern to be reviewed and each of the reference patterns "E", "V" and "X", in order to select an appropriate pair with one of the reference patterns, in accordance with the other method for selecting the appropriate pair.

FIG. 20 shows a table showing a calculation result of the necessary number of the reference patterns, and its probability, to recognize 1,000 patterns.

FIG. 21 shows a table showing membership values with regard to the measured correlation output of each of the reference patterns "E" and "V" with unknown pattern, in accordance with the inventive method of recognition and classification of the pattern.

FIG. 22 shows schematically a portion of the optical system for normalization of the correlations as detected, in accordance with the inventive optical method of recognition and classification.

FIG. 23 shows a schematic illustration of an optical system of the other type of the optical correlation processing device to be used for the inventive optical method of recognition and classification.

Detailed Description of Preferred Embodiments

In accordance with the present invention, a correlation is estimated between respective one of several patterns which should belong to several classes, and each of the reference patterns, so as to gain the correlations showing the common features between each of the respective reference pattern and the respective pattern to be reviewed, for each of the patterns to be recognized or classified, in the number same as that of the reference patterns. The set of the resulting correlations will be represented by a membership function involving the time-depending fluctuations of the spatial light modulator, and the fluctuation or change of the correlations due to speckle noise in the system.

When a pattern to be reviewed is desired to be recognized and/or classified, a comparison with said resulting membership function is carried out on the basis of the respective correlations with each of the reference patterns, and the degree of matching with the class to which the pattern shall belong can be gained by a minimum value(s) of the membership values or the average of the membership values in a certain range.

In order to classify optimally the pattern to be classified into a certain class with a small number of reference patterns, couple (pair) of reference patterns with less overlap of membership functions of each of classes in response to the same reference pattern are selected or determined, and then, the membership functions in response to such small number of the reference patterns are selected. Then, the classification of the pattern to be reviewed is carried out by comparing with the resulting membership functions on the basis of the correlation with each of the reference patterns, and matching can be gained by the minimum value of the membership values or the average value of the membership values.

The set of the reference patterns with less overlapping is selected or determined (1) calculating the number of the regions in which the area of the overlapping range of the classes exceeds the predetermined area for each of the reference patterns; (2) making a set of reference patterns by adding the reference pattern with the minimum numbers in order from least said numbers of the regions into a set of the reference patterns, producing the new set of reference patterns; (3) counting in all combination be-

tween one specified class and another specified class, the number of the overlapping ranges of the membership functions corresponding to the reference patterns having the larger area than the predetermined areas in each pair of the classes; (4) counting the number of the pair at which the said number of the overlapping ranges is in match to the said number of the reference pattern; and (5) stopping to add the reference patterns into the set of the reference patterns, and fixing the number of the reference patterns in the set, at which the counted number of the pair is less than the predetermined number.

The combination of the reference patterns in set, with less overlapping can be determined by (1) calculating the number of the regions in which the maximum membership value in the overlapping range of the classes exceeds the predetermined value for each of the reference patterns; (2) making a set of reference patterns by adding the reference pattern with the minimum number in order from least said number of the regions into a set of the reference patterns, producing the new set of reference patterns; (3) counting in all combinations between one specified class and another specified class, the number of the overlapping ranges of the membership functions corresponding to the reference patterns having the larger area than the predetermined area in each pair of the classes; (4) counting the number of the pairs at which the said number of the overlapping ranges is in match to the said number of the reference patterns; and (5) stopping to add reference patterns into the set of the reference patterns, and fixing the number of the reference patterns in the set at which the counted number of the pairs is less than the predetermined number.

The present invention is further illustrated by the following examples, but should not be interpreted for the limitation of the invention.

[EXAMPLE 1]

FIG. 1 shows schematically one preferred embodiment of the inventive optical method of recognition and classification, in an optical arrangement view.

The optical arrangement view of FIG. 1 comprises a pattern output means 1, an optical Fourier transformation means 2, a pattern output means 3, an optical Fourier transformation means 4, and an optical detection means 5.

A coherent beam 12 emitting from a source 11 such as a semiconductor laser or a gas laser is transformed by a beam expander 13 into a beam having an appropriate diameter, and is divided by a beam splitter 14 into the two beams.

A pattern to be reviewed and a group of reference patterns which have been displayed on a display plane 16 are read out by a coherent beam, and then Fourier transformed by a Fourier transformation lens 21, forming joint Fourier transformation patterns on a

screen 31. Further, the resulting joint Fourier transformation patterns are read out by a two-dimensional image sensor 32, and then the resulting pattern signals are sent to a liquid crystal driving circuit 33, which displays the patterns on a liquid crystal light valve (hereinafter referred to as "LCLV") 35, which patterns are read out by a beam 37, and again Fourier transformed by a Fourier transformation lens 41 forming Fourier transformation patterns on a screen 42, which patterns of the correlations are detected by a two-dimensional image sensor 43. A general type of such liquid crystal light valve may be a liquid crystal panel used for a liquid crystal TV and a display for a personal computer.

The respective correlation between the pattern to be recognized and each of the reference patterns is detected in the above described optical arrangement, and the resulting correlation is respectively processed in a computer 51, to gain respective membership function in correspondence respectively to each of the reference patterns. Then, the recognition of unknown pattern can be exerted by respective comparison to each of the resulting membership functions with the unknown pattern.

One example of the methods of preparation of a membership function will be described. For example, the group of reference patterns is two letters: E and V, and a pattern to be reviewed (recognized and classified) is H, and those patterns are displayed such that H is at the center, and E and V are along the same circle around H in the same distance each other, as shown in FIG. 2. Then, the output from the two-dimensional image sensor 43, which is the correlation outputs resulting from the pattern "H" respectively with each of the reference patterns appear at the positions respectively corresponding to those of the displayed reference patterns, as shown in FIG. 3, which patterns are detected as a presentation of light intensities.

The values of such correlation are indicated such that when the value is higher, the displayed circle is larger. The two parallel vertical bars and horizontal bar which constitutes "H" response with each of the reference patterns and then, the resulting correlation outputs are as indicated in FIG. 3, which shows a significant difference of the values. The auto-correlation which appears at the position of optical axis is not shown in FIG. 3 because it is not relevant.

The resulting correlation output intensity signals are sent to a computer 51, and stored in its memory. A series of patterns to be reviewed (recognized and classified) are sequentially to a display 16, and the peak value of the correlation intensities as displayed is stored in a memory of the computer 51, in sequence. There operation is repeated necessary times (multiple times) to gain a plurality of the correlation outputs respectively for each of the reference patterns.

The peak values of the correlation output inten-

sities will be fluctuated by influence e.g. of speckle (background) noise of the coherent beam, the time-dependent instability of the performance of the pattern display 16 and LCLV 35, and the input timing of the signals from the two-dimensional image sensor 32. Therefore, the one time measurement of the correlation output does not result in correct recognition and classification. Accordingly, the measurement is exerted for several necessary times to gain a plurality of data, from which the average of the peak values in response to each of the classes and its standard deviation are calculated, so as to gain a respective membership function of the peak values of the correlation output intensities in response to each of the patterns "E" and "V", which functions determining convex "fuzzy theory" sets.

For example, the range from the average value minus the standard deviation to the average value plus the standard deviation is assumed as the membership value of 1, and the outside of the range from the average value minus 3 times of the standard deviation to the average value plus 3 times of the standard deviation, i.e. the range below the average value minus 3 times of the standard deviation and the range above the average value plus 3 times of the standard deviation is assumed as the membership value of 0. In the range from the average value minus 3 times of the standard deviation to the average value minus the standard deviation, and in the range from the average value plus the standard deviation to the average value plus 3 times of the standard deviation, the membership value is indicated by the linear function, i.e. the membership function has a slope.

FIG. 4 shows a graphic illustration showing membership functions as indicating the peak value of the correlation output produced on the basis of the respective correlation resulting from each of the reference patterns "V" and "E" with one pattern "H" to be reviewed. Similarly, all of the membership functions as to all of the classes to which the patterns are to be classified are produced, and stored together with information of such classes, in a computer 51. However, in the case where the standard deviation resulting from a plurality of times of the measurement is significantly small, it is necessary to add somehow correction of the values.

When an unknown letter pattern is presented in place of "H" in FIG. 2, the resulting peak value in the correlation output intensity range resulting from the response to each of the reference patterns is sent to a computer 51, in which the peak value is compared respectively with each of the membership functions corresponding to each of the patterns to be recognized and classified.

For example, the membership functions corresponding respectively to "H", "W" and "N" are shown respectively in FIGS. 4, 5 and 6. The peak values of the correlation output intensity ranges are such that re-

spectively the coordinate at the position (a) indicates that for the pattern "E", and the coordinate at the position (b) indicates that for the pattern "V".

FIG. 7 shows a table showing how high the membership values in response to each of unknown patterns (H, N and W) are respectively at the positions (a) and (b). This table indicates only either of 1 or 0, but in general the height of each position can be located at a slanting zone, and therefore the membership value is in general analogic value.

When a "AND" estimation on a "fuzzy theory" is exerted on the membership values as shown in FIG. 7, the result is a minimum value of the membership values corresponding respectively to each of the patterns to be recognized, classified. Then, the membership values in response to the unknown patterns are 1, 0 and 0 respectively to the patterns "H", "W" and "N". Accordingly, the unknown pattern is "H" in 100 % probability. On the other hand, when there are found several "0" to the minimum values of the membership values, the minimum value will indicate the probability that the unknown pattern is it.

Further, the arithmetic mean of the membership values can be calculated from FIG. 7. In this case, the arithmetic means to the patterns "H", "N" and "W" are respectively 1, 0.5 and 0. Then, the degree of the matching to each of the patterns can be estimated. However, the estimation can be gained even when there is zero correlation with a certain reference pattern. Therefore, the AND estimation on the basis of "fuzzy theory" gives less error, and then, the arithmetic mean estimation can be used as an assistant estimation method where the AND estimation can not give any answer. When there are given only zero of the membership value to only one reference pattern, and the membership values to the other reference patterns being 1 (that may result from some shifts from the correct position when estimating the average), the AND estimation can not give any correct answer. In this case, the arithmetic mean estimation can be used as a second means for gaining the degree of the matching.

In this example, the part of the membership functions has plateau, and however, any shape can be given only provided that the curve of the membership function does not have any concave portion, i.e. convex "fuzzy theory" set (i.e. it has a maximum).

How to gain the correlation output intensities, or where to gain the correlation output intensities can be either one of that they are detected over the whole light quantity in response to the range or area of the correlation output other than the peak value, and of that they are detected by its average light quantity.

In general, the correlation output can be represented by the following equation, wherein the two patterns are represented respectively by $A(x, y)$ and $B(x, y)$;

$$I(x', y') = \iint A(x, y) \cdot B^*(x-x', y-y') dx dy$$

wherein * denotes a complex pair quantity.

It is apparent from this equation that the correlation output has the range or area which is two times of the range of the pattern. Therefore, the whole light quantity or the average light quantity from the range can be detected over the range of the correlation.

FIG. 8 shows schematically how to gain the patterns of the mutual correlation resulting from the two patterns "E" and "H", wherein the two patterns are represented on the display with some vertical slide to avoid the overlap. In this case, the correlation light quantity in response to the patterns "E" and "H" becomes at the peak, when the two pattern is completely at the same horizontal position as shown in FIG. 8 (a). And, when the patterns are slipped off or lagged in a shift length of the pattern size as shown in FIG. 8 (b), the vertical bar of the pattern "H" is vertically overlapped with the vertical bar of the pattern "E", and then, the correlation light quantity can be detected lower than the peak value.

FIG. 8 (c) shows the correlation light quantity distribution of the patterns "E" and "H" as formed, and then, the central larger circle indicates the peak light quantity, and the smaller circles up and below the central circle indicate the response to the horizontal bar, and the smaller circle horizontally apart from the central circle indicates the response to the vertical bar. Therefore, the whole light quantity or the average light quantity of those patterns gives the informations which is well responded to the features of each of the patterns. Those informations are not found in the peak light quantity.

FIG. 9 shows 15 graphs showing the relation of the membership functions produced on the basis of the respective correlation of each of the patterns (A, E, H, N, T, L, O, I, K, M, V, W, X, Y and Z) to be reviewed, with the two reference patterns (E, V) in accordance with the inventive method of recognition and classification of the pattern, wherein the solid line indicates the membership functions in response to the pattern "E", and the dotted line indicates the membership functions in response to the pattern "V", and further, the average light quantity is in an abscissa of the graph. There are found only one membership function in some cases, but this is due to that the other membership function that is not shown is beyond or out of the graph scale.

FIG. 10 is a table showing the recognition result with regard to the unknown patterns, as produced by using an experimentally obtained AND calculation method in accordance with the present invention, and the probability of the recognition result, wherein the unknown patterns are 15 patterns of the alphabet letters; A, E, H, N, T, L, O, I, K, M, V, W, X, Y and Z, and those letters are presented three times. The resulting degrees of classification to each of the letters are indicated, which degrees are estimated on the basis of the "fuzzy theory" AND estimation. The letters shown in the first column are input patterns, and the numeri-

cal values in the second and third columns in the parenthesis are the average light quantities of the correlations in response respectively to the reference patterns "E" and "V". Further, the letters at the forth column is the letter which was given or recognized by the "fuzzy theory" AND estimation using the membership values as shown in FIG. 9. The numerical values in percentage at the fifth column are the probability of the recognition.

There were found some cases in that one pattern has two or three candidacy, but the letter with the highest probability can be chosen and then all those letters could be recognized or classified by only two reference patterns "E" and "V". Such good result could not be gained in the prior art correlation processing method using commonly a self-correlation.

Further, it is apparent from the result of FIG. 10 that there are found two groups of T, L and I; and K and M in which group the letters are especially apt to be confused each other. This is because each of the letters has common features, and then, the letter with the highest probability can be selected so as to execute easily the recognition or the classification. However, even when it is desired to gain complete recognition of the letters with removing the affection due to the small number of the reference patterns, the complete recognition can be accomplished merely by simple processing. The processing in which one reference pattern to produce membership function without overlapping range in response to the confusable letter should be entered or added into the set of the reference patterns can enable to accomplish the complete recognition or classification of the letters. The "fuzzy theory" AND calculation can enable to identify different letter when it has only one membership value being 0.

Further, when the classes or patterns to be classified or recognized are larger, i.e. the number of the classes or patterns is raised, it can be readily coped with. The membership functions in response to the raised number of the classes or the patterns can be easily estimated or gained in accordance with the above-described method. In this case, it is unnecessary to carry out the processing such as retraining to change weights of the connections to connect neurons of the artificial neural network. When the classes or patterns to be reviewed are increased in the artificial neural network, there will be raised problems of increase of retraining time because the number of the used neurons is increase, but, there is not found such problem in this method of recognition or classification of the patterns.

When this method is applied to the association of the patterns, the width or the range of the membership function may be increased or larger than the range of the above-described membership function. Especially, the original (perfect) pattern can be associated or regenerated from an imperfect pattern by using the

wider range of the correlation intensities, i.e. extending the the range of the membership functions to the lower correlation side. Further, the major patterns can be associated or regenerated from the informations or the patterns containing excess information, by using the wider range of the correlation intensities, i.e. by extending the range of the membership functions to the higher correlation side.

Further, it can be used for judgement as to whether the pattern is imperfect or not. In this case, the processing is in reverse to the association processing, and when the correlation output is found exceeding the area of the membership function which is gained including the fluctuation of the intensities due to the optical arrangement, e.g. when the observed correlation intensity expands beyond the value of plus 3 times of the standard deviation, the pattern is decided to be imperfect or defective.

In this example, 15 patterns can be recognized or identified by using merely two reference patterns. The performance of this method can be considered, or reviewed as follows:

When the dynamic range of the correlation output to be detected is 1:100, and the area in which the membership value to one membership function is not zero is 10, there are provided 10^N of orthogonal ranges for N reference patterns. Therefore, the patterns to be recognized may be easily positioned or distributed in such ranges, and then, significantly many different patterns can be recognized or classified by using merely a few number of the reference patterns. Further, this method is based on the "fuzzy theory" AND estimation, and then, when the "fuzzy theory" judgement can be implemented, it is unnecessary to assign the membership functions to each of the completely orthogonal ranges, and then, the number of the patterns to be recognized or classified are significantly raised to the tremendous number.

Further, when the peak values of the correlation output, and the average light quantity of the receiving (detection) range corresponding to the area of the correlation pattern are used for the basis to calculate a membership function, two different informations in response to each of the reference patterns can be afforded. Accordingly, the number of the necessary reference patterns can be further reduced, and then, more reliable recognition and classification can be gained from more informations.

In this example, a joint Fourier transformation correlator was used for an optical system to gain the correlation output. Then, this case is advantageous in that addition of reference pattern(s) and rewriting out are easily effected. When it is desired to improve the performance of recognition and classification, a joint Fourier transformation device is not advantageous. Where the reference patterns and the patterns to be reviewed are Fourier transformed in parallel, the contrast in the multiple interference fringes formed on the

screen 31 of FIG. 1 is decreased with increase of the number of the reference patterns, and then, the intensities of the gained correlation outputs are lowered, so as to decrease the dynamic range to which the membership functions are assigned or allotted, thereby lowering substantially the performance of recognition of the patterns.

Accordingly, the above described correlation processing method to avoid the lowering of the correlation output is more efficient. Then, this processing method will be illustrated in the following example.

[EXAMPLE 2]

FIG. 11 shows schematically the structure of one of the optical correlation processing apparatus using matched filtering. FIG. 11 illustrates an optical arrangement of regenerating a known matched filter. A matched filter 61 has a multiple record which record has been stored by changing an irradiation direction of plane wave beam respectively to each of the reference patterns. As shown in FIG. 11, the beam 12 emitting from a laser source 11 is expanded to an appropriate diameter of the beam by a beam expander 13, and irradiates a pattern to be recognized, which has been formed on a display 16. Then, the beam having a complex amplitude distribution of the pattern is Fourier transformed by a Fourier transformation lens 21, and irradiates a multiple interference fringe pattern formed on a matched filter. Thereby, a diffraction beam is emitted in a direction of a plane wave which has been used for forming the Fourier transformation patterns of reference patterns on the filter, from the corresponding Fourier transformation patterns of the reference patterns having the same frequency as that of the pattern to be recognized.

The diffraction beam is focused on a screen 31 by a focusing lens 22, forming a cross-correlation between the pattern to be recognized and each of the reference patterns, and further forming a convolution between them. Because the positions of the cross-correlation patterns to be represented have been known, the peak values of the correlation output intensities at those position or the whole light quantities around those positions can be easily detected.

Further, correlation output intensities regarding the other patterns to be recognized are similarly detected. The process for gaining a membership function is similar to that of Example 1, and then, is not described again.

In this example, a matched filter does not have overlap of Fourier components among the reference patterns, and then, the lowering of the contrast in the correlation outputs due to the increase of the number of the reference patterns is not so much. Therefore, the lowering of the dynamic range to be assigned to the membership functions is not so much, and then, significantly more patterns can be recognized by

using less number of the reference patterns.

Further, the other type of joint Fourier transformation correlator can be used to give similar processing result. For example, an array of lenses can be used to Fourier transform separately and in parallel and in joint each of the reference patterns and patterns to be recognized. Thereby, there is resolved a problem of overlapping Fourier components of each of the reference patterns to lower the contrast of cross-correlation intensities to result from the reference patterns and the patterns to be recognized. Further, addition of reference patterns and substitution of reference patterns can be enabled, giving flexibility of the processing. For example, it can satisfy the need of partial substitution of the reference patterns when the ready set of the reference patterns can not completely recognize (separate) the patterns to be recognized.

Examples 1 and 2 use a coherent beam, and then the parallel shift is very strong. This is because of that the positions of the correlation outputs as formed are in parallel shifted or moved depending on the parallel shift of the input patterns.

The next Example illustrates a relatively simple optical arrangement which can be easily integrated.

[EXAMPLE 3]

FIG. 12 shows a schematic illustration of an optical system of the known type using an incoherent beam. In this optical arrangement, a display 16 and a mask 62 for reference patterns are closely assembled, so as to focus a output of a product between a pattern to be recognized on a display 16 and each of reference patterns formed, on a screen 62 by using an array 71 of focusing lenses, and then the outputs from the resulting focused each of the reference patterns are detected by a two dimensional photo image sensor 43.

Pattern to recognize is arranged in array on a display 16, using each of elements corresponding respectively to each of masks 62 for reference patterns.

In this example, a cross correlation peak resulting from the pattern to be recognized and each of the reference patterns is detected. Following the above operation, further the other patterns to be recognized are displayed in sequence on the display, and then, membership functions corresponding to each of the reference patterns are prepared for each of the patterns to be recognized, and then the processing same as that of Examples 1 and 2 can be done. However, there is no allowance to parallel shift of input patterns, but the device in accordance with this method has simple struction and then can be easily integrated.

[EXAMPLE 4]

FIG. 1 shows generally a structure of a typical

joint Fourier transformation optical system to be used for an optical correlation processing system.

The optical arrangement of FIG. 1 has a pattern output means 1, an optical Fourier transformation means 2, a pattern output means 3, an optical Fourier transformation means 4 and an optical detection means 5.

A coherent beam 12 emitting from a laser source 11 reads out a pattern to be recognized and each of reference patterns formed on a display 16, and focused on a screen 31 by a Fourier transformation lens 21, forming joint Fourier transformation patterns. These Fourier transformation patterns are read out by a two dimensional photo image sensor 32, and displayed on a LCLV 35 of electric addressing type through a liquid crystal driving circuit 33. The displayed patterns are read out by a beam 37, which beam is focused on a screen 42 by a Fourier transformation lens 41, forming correlation intensities, which patterns are detected by a two dimensional image sensor 43.

In the inventive method, a correlation between a pattern to be recognize and each of reference patterns is detected by the above mentioned optical arrangement, and then, each of the membership functions is prepared on the basis of respective correlation (degree) between each of the patterns to be reviewed and each of the reference patterns, and the prepared membership functions are respectively compared with each other so as to gain recognition or classification of the unknown patterns to be reviewed.

The membership function is gained as follows:

FIG. 13 shows schematically respective position of one pattern (H) to be reviewed and reference patterns (E, V, X) as presented on a display correlator 16, in case which the joint Fourier transformation optical device is used for production of the membership function. Each of the patterns is apart from each other at similar distance, in which the reference patterns E, V and X are along the same circle of the center of the pattern H. The output of respective correlation between the letter H and each of the reference letters, i.e. the output from a two-dimensional image sensor 43 is respectively represented at the positions corresponding respectively to the positions of each of the reference letters, and can be detected as a light intensities as shown in FIG. 14.

Here, when the peak value of the correlation output is higher, the circle as shown is larger. Each of two parallel vertical bars and horizontal bar constituting the letter "H" will response respectively to each of the vertical bar(s) and horizontal bar(s) of respective reference pattern, so that there is occurred difference in correlation output as shown in the drawings. The output of the auto-correlation which will appear on an optical axis is not shown in FIG. 14. FIG. 14 shows schematically the respective cross-correlations on the basis of one pattern to be reviewed and the refer-

ence patterns as shown in FIG. 13, in case which the jointed Fourier transformation optical correlator is used for recognition and classification of pattern.

The output of the respective correlation as detected is sent to a computer 51 of FIG. 1, and stored therein, and then, the each of the patterns to be reviewed is shown on a display device 16. Then, the respective peak of the outputs as shown on the display device 16 is detected and stored respectively in a computer 51. Further, such processing is carried out several times for each of the patterns to be reviewed. There will be occurred fluctuation of the peaks of the correlation output, because of speckle noise of the used coherent beam, time passage instability of a display device 16 and a LCLV 35, and of fluctuation of input timing of the signals fed from a two-dimensional image sensor 32. Mere one time of measurement of correlation outputs does not have enough creditability of the data for gaining correct recognition and classification. Therefore, in accordance with the inventive method, firstly an average of the peak of the correlation output respectively in response to the patterns E, V and X, and the standard deviation of the measured output are calculated, and then, the respective membership function of the correlation outputs regarding each of the patterns E, V and X is assumed as a shape of trapezoid, e.g. the membership value at the range from the average value to over the standard deviation is assumed to be 1, and the membership value at the range from the average plus three time of the standard deviation is 0, so that the slope of the trapezoid shape has the length of one to three times of the standard deviation.

FIG. 15 shows a graph showing schematically the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns (V, X, E) with one pattern (H) to be reviewed in accordance with the inventive method of recognition and classification of the pattern. Further, the membership functions respectively regarding to all of the classes to be reviewed are prepared, and they together with information of the classes to be reviewed are stored in a computer 151. Further, somewhat correction should be carried out if necessary because standard deviation may be exceptionally low only from the small number of measurement.

A unknown pattern to be reviewed can be recognized by counting a membership value of the respective membership function in response to each of the reference patterns with each of unknown patterns, and then regarding the minimum membership value among the counted membership values or the average of the counted membership values as a degree as to how the pattern to be reviewed belongs to the specified class. Accordingly, with only small number of the reference patterns as small as possible, the set of the reference patterns having high performance of recognition or classification can enable to gain higher probability of the recognition or to reduce error of rec-

ognition as well as to reduce significantly needed time for recognition or classification of patterns.

The set of the reference patterns can be gained as follows:

FIG. 15 shows a graph showing schematically the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns (V, X, E) with one pattern (H) to be reviewed in accordance with the inventive method of recognition and classification of the pattern.

FIGS. 16 and 17 are a graph respectively showing the relation of the membership functions produced on the basis of the respective correlation of each of the reference patterns (V, X, E) respectively with another pattern to be reviewed, and with the other pattern to be reviewed.

The following processing should be carried out to classify rationally with the number of the used reference patterns being as low as possible. First of all, the area of the range with overlapping of the membership functions regarding to the same reference pattern is regarded as a degree of overlapping, and then, the number of the regions in which the area of overlapping is larger than the predetermined value is counted. The reference pattern having second minimum number would be added to the reference pattern having the most minimum number and they would be added to the set of the reference patterns, and the processing should be repeated to gain appropriate result of recognition or classification of patterns.

Next, the number of the regions in which the area of the overlapping range of the classes exceeds the predetermined area for each of the reference patterns is estimated, and a set of reference patterns by adding the reference pattern with the minimum number in order from least said number of the regions into a set of the reference patterns is made to produce the new set of reference patterns, and then, among all combinations between one specified class and another specified class, the number of the overlapping ranges of the membership functions corresponding to the reference patterns having the larger area than the predetermined area is calculated for each pair of the classes, and the number of the pairs at which the said number of the overlapping ranges is in match to the said number of the reference patterns is counted, and then, it should be stopped adding the reference patterns into the set of the reference patterns when the number of the reference patterns in the set at which the counted number of the pairs is less than the predetermined number.

For example, the species of the combination of two patterns selected from three patterns H, N and V is 3, and then, the membership functions for the three species are prepared, and then the ranges of overlapping respectively in regard to each of the reference patterns are measured, and the result is shown in FIG. 18.

FIG. 18 shows a table showing a calculated overlap area of the membership functions, resulting from the pair of patterns to be reviewed and each of the reference patterns "E", "V" and "X", in order to select an appropriate pair with one of the reference patterns. Here, when the area of overlapping of the membership functions in response to each of the reference patterns is larger, it can be more difficult to recognize the patterns. Accordingly, when it is desired to recognize completely the patterns, the case in which the overlapping area is relatively large is not good. Assuming that the case in which the overlapping area is larger than 0.5 is a confusable case in which error of the recognition can occur, and then the number of the regions in which the overlapping area is larger than 0.5 is counted. Then, such number in regard to each of the reference patterns E, V and X is counted to be respectively 1, 2, and 3. Then, first of all, the pattern "E" having minimum overlapping degree is selected, and then, the pattern "V" having next minimum overlapping area is selected. In this case, the set of the reference patterns has 2 patterns, and the number of the regions in which the overlapping area of the membership functions is larger than 0.5 is one among two combinations of the two reference patterns E and V and then in this case, the number of the pairs at which the number of said regions is in match to the number of the reference pattern is 0. Therefore, those three patterns can be recognized or classified by using only a set of two reference patterns E and V, and then the pattern X is unnecessary. If the number of the pairs at which the number of regions is in match to the number of the reference patterns is several, it is a little difficult for some class to recognize the patterns to be tested. In such case, adding the reference pattern to the set of reference patterns is stopped by admitting not to recognize some classes. In other words, When the prepared membership functions are much overlapped each other in special classes or cases, it will be difficult to discriminate the patterns each other.

A rational set of the reference patterns can be selected on the basis of another standard. First of all, the maximum membership value in the overlap range in which the membership functions formed from cross-correlation of the patterns to be reviewed overlap each other is regarded as a degree of overlap, and then, the number of the regions in which the maximum membership value is larger than the predetermined value is counted. Then, the pattern with least such number is in sequence added to the set of the reference patterns so as to produce a new set of the reference patterns. Among all combinations of two reference patterns, the number of the cases in which the number of the selected (or fixed) reference patterns contained in the set is in match with the number of the regions in which the membership functions in response to the same reference pattern having the overlap area larger than the predetermined value is

counted, and then when the counted number becomes less than the desired number, the addition of further reference pattern to the set of the reference patterns is stopped.

For example, there are three combinations resulting from three patterns H, N and W, and then, the maximum membership value in the overlap range of each of the membership functions in response to each of the reference patterns is estimated or measured, and the result is shown in FIG. 19. Here, when the maximum membership value in the overlap range of the membership functions in response to each of the reference patterns is higher, it will be difficult to recognize or to discriminate the two patterns to be reviewed. Therefore, when it is desired to discriminate completely two patterns, the case in which the maximum membership value is considerably higher than 0 is not good. Then, the region in which the maximum membership value in the overlap range of the membership function curves in response to each of the reference patterns is higher than 0.5 should be regarded as confusable, and then, the number of the regions in which such maximum value is higher than 0.5 is counted to be 1, 2 and 3 respectively in regard to the reference patterns E, V and X. Then, the pattern E having least overlapping is selected, and then, the pattern V having next less overlapping is selected as a reference pattern. Therefore, the set of the reference patterns has two patterns. The number of the regions in which the maximum value is higher than 0.5 among the overlap range of the membership function curves is 1 for all combinations of patterns to be reviewed. Therefore, the reference patterns to discriminate the pattern are the patterns E and V, and the pattern V is not necessary.

Where a overlap area of the membership functions is used as a standard as to how much the pattern to be reviewed should belong to the reference patterns, the range wider than the width of the standard deviation can be corresponding to the slope of the trapezoid of the membership function curve, and the probability of detecting the correlation pattern within this range will be statistically 33 percent. Then, the overlap area can indicate the distribution of its probability, and therefore, when unknown pattern is recognized, high adaptability will be found. On the other hand, where the maximum membership value in the overlap range is used as a standard as to how much the pattern to reviewed should belong to the reference patterns, the worst value in the recognition processing can be considered in the recognition processing.

The membership values resulting from the correlation of each of unknown patterns and the respective membership function of each of the reference patterns can be estimated, and then, the minimum value of the membership values or the average of the membership values can be estimated to be used as a standard of the recognition.

FIG. 19 shows a table showing a calculated maximum membership values, resulting from the pair of respective patterns to be reviewed and each of the reference patterns "E", "V" and "X", in order to select an appropriate pair with one of the reference patterns. There is possibility of that the worst membership value is 0.2 in regard to the patterns H and W with using the reference patterns E and V. In this case, two pattern can not be discriminated. However, this case is rare case, and such case does not occurred in practice.

The following consideration can be taken on the above methods. For example, where N of reference patterns without less overlap at Fourier transform plane are ready to be used, and the number of patterns to be reviewed or recognized is M, and the range having the width of three times of the standard deviation is R, and the dynamic range of the detector is D, the range without overlap, i.e. the number of orthogonal-regions $B = D/R$. "Orthogonal region" means a region to which one pattern is assigned so that the pattern is not confused with the other pattern. Here, assuming that the spatial frequency of the pattern to be reviewed will have random distribution, it can be understood in term of probabilities (statistics). The number G of cases in which N of the reference patterns can be entered into B of the regions, in regard to one specified class: $G = B^{(N+M)}$. On the other hand, a complete recognition will need that M of the classes have respectively one difference region, in correspond to all of the cases.

Therefore, the number of such cases is $G P_M$. Then, the probability thereof P is in the following equation.

$$P = G P_M / G$$

Assuming that the classes to be reviewed are 1,000, and the number of the orthogonal regions are 10 or 20, it will be reviewed how many reference patterns is necessary, and then, the table of FIG. 20 is presented. "Transposition areas" in the table means the number of the "orthogonal regions". It is apparant from this table that the necessary number of reference patterns will be respectively 8 and 7 in cases that the number of the orthogonal regions are 10 and 20. Therefore, the degree of overlap of the membership function curves should be considered while reference pattern should be added to the set of the reference patterns, which will lead to the combinations of reference patterns to discriminate unknown patterns.

Using the set of the reference patterns E and V, the method of recognition will be described. Unknown pattern is used in place of the letter "H" in FIG. 13, and the respective peak of the correlation outputs in response to each of the reference patterns is detected and stored in a computer 51 of FIG. 1, and compared with the membership function curves of each of the patterns to be recognized. For example, the membership function curves are estimated respectively on FIGS. 15, 16 and 17. The respective

peak of the correlation output resulting from with the unknown pattern is observed, i.e. the outputs corresponding respectively to the position of "a" point for the reference pattern E and "b" point for the reference pattern V.

FIGS. 18 and 19 shows a table showing a calculated overlap area of the membership functions, resulting from the pair of unknown pattern and each of the reference patterns "E", "V" and "X", in order to select an appropriate pair with one of the reference patterns. In this example, the resulting membership values are anagoric, as shown in the tables, which indicates the value at the range of the slope of the trapezoid of the membership function curves.

FIG. 21 shows a table showing how much (or high) the membership values in response to each of unknown patterns (H, N and W) are respectively at the positions "a" and "b".

The membership values of FIG. 21 suggests that a fuzzy theory AND calculation can be proceeded to gain a minimum of the membership value in response respectively to each of the patterns to be recognized, and the minimum of the membership value is 1, 0 and 0 respectively in response to the reference patterns H, W and N to be reviewed, and therefore, the unknown pattern shall be H with probability of 100 %. On the other hand, when there are found several cases in which the minimum is not 0, the degree as to how much the pattern should belong to the specified class can be judged on the basis of the minimum.

Further, the arithmetic mean of the membership value as shown in FIG. 21 can be used to judge such degree, i.e. the respective mean in response to the patterns H, W and H in regard to unknown pattern is respectively 1, 0.5 and 0. Therefore, the degree of recognition of unknown pattern can be somehow confirmed or found. However, where the arithmetic mean is used, there is possibility of error correlation (the membership value is 0) with a certain reference pattern but the answer can be obtained. The "fuzzy theory" AND calculation can avoid error, but the arithmetic mean can be used when the "fuzzy" calculation is difficult. For example, when there is occurred that the membership value is 0 to one reference patterns, but the values to the other reference patterns is 1, and then, the AND calculation does not give correct answer, the arithmetic mean should be used as a next means.

In this example, the part of the membership function curve has plateau, and the curve of the membership function can be any shape having no convex, to which the "fuzzy theory" can be applied. In this example, the standard deviation is taken as a basis for preparation of membership functions, and the width of three times of the standard deviation is regarded as a degree of the range of the membership function, but the other parameter can be used to judge the degree. For example, when the range in which the member-

ship value is 1 shall be in the width of two times of the standard deviation, the correlation output can be detected in about 97 % in a statistic view. Therefore, about 100 % of the classes to be recognized can be detected, but the membership function will be broaden, and then, it becomes somehow difficult to discriminate from the other class.

The correlation output can be detected from the whole range of the output pattern except of the peak value to gain the whole light power or the average light power of the detection range. The correlation output $I(x', y')$ can be represented by the following equation wherein the two patterns are represented by $A(x, y)$ and $B(x, y)$.

$$I(x', y') = \iint A(x, y) \cdot B^*(x' - x, y' - y) dx dy$$

wherein * denotes a complex paired (conjugated) quantity.

From this equation, it is apparant that the correlation output has the width of two times of the diameter of the pattern. Therefore, the whole light power or average power in this range can be taken from the peak value.

FIG. 8 shows schematically how to gain the pattern distribution of the mutual correlation resulting from the two patterns "E" and "H", to be used for recognition and classification of pattern. In this case, the pattern E and the pattern H are vertically shifted to avoid the overlap. The output of the correlation between the patterns E and H becomes a peak value as shown in FIG. 8 (a) when the two patterns are completely overlapped, and the light power due to the correlation can be lower than the peak value, due to that the vertical one bar of the pattern H is overlapped with the vertical bar of the pattern E as shown in FIG. 8 (b) when the two patterns are shifted in a distance of the pattern size.

FIG. 8 (c) shows the light power of the correlation between the patterns E and H, wherein the larger circle at the center indicates the light power of the peak, and the smaller circles vertically apart from the center indicate the power of the horizontal response, and the smaller circle horizontally apart from the center indicates the power of the vertical bar. Therefore, those powers or average powers have respective feature or information of each of the patterns, which feature is not shown in the peak light power.

FIG. 9 shows 15 graphs showing the relation of the membership functions produced on the basis of the respective correlation of each of the patterns (A, E, H, N, T, L, O, I, K, M, V, W, X, Y and Z) to be reviewed, with the two reference patterns (E, V). The real curve indicates the membership function in regard to the pattern E, and the dotted line indicates the membership function in regard to the pattern V, and the average light power of the correlation output is plotted in coordinate. In some cases, there is found only one membership function, which suggests that another function can not be indicated in the scale of the graph.

FIG. 10 is a table showing the recognition result with regard to the unknown patterns, as produced by using an experimentally obtained AND estimation method, and the probability of the recognition result. The unknown patterns are the same as in FIG. 9, wherein three time measurement is presented by using "fuzzy theory" AND calculation, to present the recognition result of each of the letters. The resulting degrees of classification to each of the letters are indicated, which degrees are estimated on the basis of the "fuzzy theory" AND estimation. The letters shown in the first column are input patterns, and the numerical values in the second and third columns in the parenthesis are the average light quantities of the correlations in response respectively to the reference patterns "E" and "V". Further, the letters at the fourth column is the letter which was given or recognized by the "fuzzy theory" AND estimation using the membership values as shown in FIG. 9. The numerical values in percentage at the fifth column are the probability of the recognition.

There were found some cases with some confusion, i.e. bad recognition, i.e. one pattern has two or three candidacy, the letter with the high probability can be chosen, but it can be concluded from the better result, i.e. the cases in that the letters can be recognized with high probability that all those letters could be recognized or classified by only two reference patterns "E" and "V". Such good result could not be gained in the prior art correlation processing method using commonly an autocorrelation.

In this example, the set of the reference patterns can be made as shown in FIGS. 18 and 19, the set of the reference patterns E and V can enable to discriminate completely three patterns H, N and W, and the separation of the other letters is not enough.

Further, it is apparent from the result of FIG. 10 that there are found two groups of T, L and I; and K and M in which group the letters are especially apt to be confused each other. This is because each of the letters has common features, and then, the letter with the high probability can be selected so as to execute easily the recognition or the classification. However, even when it is desired to gain complete recognition of the letters with removing the affection due to the small number of the reference patterns, the complete recognition can be accomplished merely by simple processing. The processing in which one reference pattern to produce membership function without overlapping range in response to the confusable letter should be entered or added into the set of the reference patterns can enable to accomplish the complete recognition or classification of the letters. The "fuzzy theory" AND calculation can enable to identify different letter when it has only one membership value being 0.

Further, when the classes or patterns to be classified or recognized are larger, i.e. the number of the

classes or patterns is raised, it can be readily coped with. The membership functions in response to the raised number of the classes or the patterns can be easily estimated or gained in accordance with the above-described method. In this case, it is unnecessary to carry out the processing such as retraining with supervision to change weights of the connections to connect neurons of the artificial neural network. When the classes or patterns to be reviewed are increased in the artificial neural network, there will be raised problems of increase of retraining because the number of the used neurons is increased. But, if the enough number of the reference patterns is prepared to be used, such problem of confusion due to overlapping can be avoided.

When this method is applied to the association of the patterns, the width or the range of the membership function may be increased or larger than the range of the above-described membership functions. Especially, the original (perfect) pattern can be associated or regenerated from an imperfect pattern by using the wider range of the correlation intensities, i.e. extending the range of the membership functions to the lower correlation side. Further, the original patterns can be associated or regenerated from the informations or the patterns containing excess information, by using the wider range of the correlation intensities, i.e. by extending the range of the membership functions to the higher correlation side (The membership function has wider slope to extend from 3 times of the standard deviation to 4 or 5 times of the deviation).

In this case, the range of the membership function extends for region of imperfect pattern, or the pattern containing excess information, so the degree of overlapping among the membership functions will be higher. There is less orthogonal regions, and then the number of the patterns which can be recognized or discriminated will be decreased.

Further, it can be used for judgement as to whether the pattern is imperfect or not. In this case, the processing is in reverse to the association processing, and when the correlation output is found exceeding the area of the membership function which is gained including the fluctuation of the intensities due to the optical arrangement, e.g. when the observed correlation intensities expands beyond the value of plus 3 times of the standard deviation, the pattern is decided to be imperfect or defective.

The pattern containing excess information, so that the degree of cross region among the membership functions is bigger and there is less orthogonal region, and then the number of the recognized patterns will decrease.

For example, there are provided as shown in FIG. 22, a beam splitter 117 between a pattern display 116 and a Fourier transformation lens 121, and a whole light quantity emitted from the pattern to be reviewed

and the reference patterns is detected by a two-dimensional image sensor plane 144, which is transmitted to a computer 151 so as to enable processing of the correlation. The other optical arrangement is same as that of FIG. 1 and then is not shown in FIG. 22.

FIG. 22 shows schematically a portion of the optical system for normalization of the correlations as detected.

Upon using the light powers, the correlation powers corresponding to the pattern to be reviewed and each of the reference patterns are normalized to obtain normalized values. For example, when the correlation light power in response to each of the reference patterns is X_N , and the reduction of the correlation light power when the imperfect pattern is entered is Δ_N , the correlation power in response to the imperfect pattern is $X_N - \Delta_N$ in non-normalization. When the normalization is proceeded, the light power of the perfect pattern is A, and the reduction in the light power of the imperfect pattern is D, the normalized values of the correlation light power are X_N/A for the perfect pattern, and $(X_N - \Delta_N)/(A - D)$ for the imperfect pattern. Then, where the reduction is not significant, $A > D$, $(X_N - \Delta_N)/A * (1 + D/A)$ for the imperfect pattern. Therefore, the difference in the normalized value is D/A , and then, the reduction can be lowered in such degree.

Accordingly, the number of the classes to be reviewed can be increased in the corresponding degree. Further, the normalization on the basis of the whole power of the pattern to be reviewed and the reference patterns can remove somehow a fluctuation of the performance of a spatial light modulator, and its instability, and imperfectness of the pattern. The light power of the reference patterns is B, the shift due to the fluctuation of the spatial modulator is E, and then, $B > E$, and the light powers of the correlation respectively when the pattern is perfect and imperfect are $X_N/(A + B)$, and $(X_N - \Delta_N)/(A - D + B - E)$. Further, when the fluctuation is lower, and imperfectness is less, $A + B > D + E$. Therefore, the normalization on the basis of the light power of the pattern to be reviewed gives a reduction of $(D + E)/(A + B)$, then, the affect ion by the imperfectness of the pattern and the fluctuation of the spatial light modulator can be removed to some extent.

Further, it can be used to judge whether the pattern is imperfect or not. In this case, in contrary to the association processing, if the rage of the membership function including the fluctuation is broader than the diameter of three times of the standard deviation, the pattern is judged to be imperfect.

Further, when the peak values of the correlation output, and the average light quantity of the receiving (detection) range corresponding to the area of the correlation pattern are used for the basis to calucalate a membership function, two different informations in

response to each of the reference patterns can be afforded. Accordingly, the number of the necessary reference patterns can be further reduced, and then, more reliable recognition and classification can be gained from more informations.

Because the dynamic range of the two-dimensional detector of detecting the correlation output will be limited, the whole light power can not be received in some cases. Then, the maximum of the correlation output, i.e. the peak of the correlation output should be adjusted to a upper maximum sensitivity of the two-dimensional image sensor so that all of the peaks can be detected with correct sensitivity. However, when the whole power or the average light power should be detected over a whole range of the correlation output, the power other than the peak can not be detected to gain considerable height. In this case, the maximum sensitivity of the detector should be adjusted to the height lower than the peak of the correlation output, and then, the sensitivity to detect the light power at the neighbor of the peak position will be saturated, and then, the surrounding location pattern output can be efficiently detected with good linear response. Therefore, the effective and useful dynamic range of the detector can be used, so that the whole light power or the average power detected will be significantly useful.

In this example, a joint Fourier transformation correlator was used for an optical system to gain the correlation output. Then, this case is advantageous in that addition of reference pattern(s) and rewriting out are easily effected. When it is desired to improve the performance of recognition and classification, a joint Fourier transformation correlator is not advantageous. Where the reference patterns and the patterns to be reviewed are Fourier transformed in parallel, the contrast in the multiple interference fringes formed on the screen 31 of FIG. 1 is decreased with increase of the number of the reference patterns, and then, the intensities of the gained correlation outputs are lowered, so as to decrease the dynamic range to which the membership functions are assigned or allotted, thereby lowering substantially the performance of recognition of the patterns.

Accordingly, the correlation processing method to avoid the lowering of the correlation output is more efficient. Then, this kind of processing method will be illustrated in the following example.

[EXAMPLE 5]

FIG. 23 shows schematically an optical arrangement for regeneration of the known matched filter. A used matched filter 161 has a multiple record of multiple reference patterns by changing the irradiation direction of a plane wave, corresponding to each of the reference patterns. A beam 112 emitting from a laser source 111 is expanded in its diameter into an

appropriate diameter by a beam expander 113, and irradiates the pattern to be recognized as displayed on a display device. Then, a beam having a complex amplitude distribution of the patterns is Fourier transformed by a Fourier transform lens 121, and then irradiates the multiple interference fringe patterns presented on a matched filter. Then, the diffraction beams(light) are emitted (radiated) in the directions of the plane waves which have been used to prepare the reference patterns, respectively from the presented reference patterns having the frequency spectrum same as that of the pattern to be recognized.

This defraction beam is focused on a screen 131 by a focusing lens 122, and then, one of the diffraction beam will have the cross-correlation pattern between the pattern to be recognized and each of the reference patterns, and the other one of the diffraction beam will be a convolution. Therefore, because each position of the reference patterns to appear is known, the peak and the whole light power of the cross-correlation output can be easily detected.

Such processing to detect the peak and whole power of the cross-correlation pattern can be repeated, and each of the membership functions can be easily made in a similar way to that of example 4.

In this case, a matched filter does not have overlap of auto-Fourier transform components formed from each of the reference patterns, and then, the contrast of the correlation output can be raised by increasing the number of the reference patterns. Therefore, the dynamic range to be lotted to the membership functions can be readily increased, and then, a small number of the reference patterns can discriminate significantly many patterns.

The above described matched filter has been prepared by a Fourier transform hologram technique, and then a Fourier transform hologram can be used for the same purpose.

The other type of joint Fourier transformation device can be used to get the similar effect of the correlation processing.

Joint Fourier transformed patterns of each of reference patterns with the pattern to be reviewed can be easily obtained by using array of lenses. In this method, the reference patterns can be mutually overlapped so that the problem of decreasing the contrast of the cross-correlation outputs could be removed. The reference pattern can be easily added or rewritten in contrary to the matched filtering method, and more flexible processing can be enabled. For example, when the ready set of the reference patterns can not discriminate enough patterns, it can be easily to satisfy the need of rewriting of portion of the set of the reference patterns.

Examples 4 and 5 are based on a coherent beam system, in which the parallel shift of the input patterns formed is not so much. This is because of that the position of the correlation output is moved depending

on the parallel shift of the input pattern.

The next Example illustrates a relatively simple optical system which can be easily integrated.

[EXAMPLE 6]

Next, the integration of the devices is illustrated by a simple optical embodiment.

FIG. 12 shows a known optical arrangement using an incoherent beam. In this arrangement, a display 116 is arranged closely to a reference pattern mask 162, so that the output of a product of a pattern to be reviewed and the reference patterns formed on the display 116 is focused on a screen 131 by using a focus lens array 171, and then, the output from each of the reference patterns as formed on a two-dimensional photo transducing element 43 is detected.

The patterns to be reviewed are arranged in array on a display device 116, in regions in response to the reference pattern mask 162.

In this case, the respective peak in the cross-correlations of each of the reference patterns and the pattern to be reviewed can be detected. Further, another pattern to be recognized is in sequence presented on a display device, and membership functions of which the number is the same as the number of the reference patterns are prepared on the basis of the output of the pattern to be recognized, in the similar way to that of Example 4. However, the parallel shift of the input pattern can be allowed in such way, but its device can be simplified, and further easily integrated.

any kind of optical correlation processing means can be used in the above example. Further, there are proposed various kinds of joint Fourier transducing correlation means. For example, a light addressing type of liquid crystal light valve can be used in place of an electric addressing type of liquid light valve 35 in FIG. 1 using a screen 31, a two-dimensional transducing element 32 and a pattern processing device 33.

The element to function as a spatial light modulator in the inventive method can be of electric addressing type and of optical addressing type. Examples of the electric addressing type may be a liquid crystal panel as used in the above Example, and a ceramic element and crystal having a photoelectric effect, such as PLZT, KDP and BSO ($\text{Bi}_{12}\text{SiO}_{20}$) provided with matrix electrodes.

Examples of the optical addressing type may be the structure including the similar ceramic material combined with a photoconductive layer.

The material having a photorefractive effect, such as BSO and BaTiO_3 can change the refractive index induced by the electric field of photo-induced electrocn charge of the material depending on the intensity of the incident beam, and then, there is no need of providing a photoconductive layer. Such spatial light modulator may be of transparent type or of ref-

lecting type. However, when the reading-out beam will erase wholly the information formed in the element of optical addressing type by the addressing beam, the wavelength range of the reading-out beam should be separated from that of the addressing beam in order to avoid the influence of the reading-out beam to the recorded information.

When the element of the electric addressing type is used, the two dimensional image sensor and the driving circuit to drive the electric addressing one are necessary to produce the input image, and therefore, there is provided an advantage of facilitating to process those signals therefor.

The inventive method can enable to recognize and classify a significantly large number of the patterns, even with provision of relatively lower number of the reference patterns.

The uncertainty of analogic processing, or optical processing of patterns can be removed by calculation of membership function considering fluctuation due to time passage of spatial light modulator, and/or time fluctuation due to speckle noise on the basis of statistic parameters or statistic theory.

Each of the correlations between the pattern to be classified and each of the reference patterns is calculated, and then, each of membership functions is calculated, and each of membership values is estimated from the membership functions using "fuzzy theory" AND calculation so that significantly correct recognition and classification of patterns to be classified can be provided.

An appropriate combination of reference patterns is determined, and then, the provision only of a small number of reference patterns can enable to recognize or classify the patterns to be reviewed, in a very high speed, and with high correctness. If an additional pattern to be recognized or classified is added to the set of the patterns to be recognized, an additional membership function of the respective correlation of this additional pattern with each of the reference patterns can be easily prepared, so that recognition of the additional pattern can be easily proceeded.

Even where the recognition of pattern is confusable, the probability of the recognition can be easily improved by adding one or a small number of reference patterns to the old set of reference patterns so as to produce a new set of reference patterns enabling complete recognition of patterns. The width of the range of the membership function can be adjusted depending on the utility such as recognition, classification and association of patterns, independent to the fluctuation in the optical process. Then, flexible treatment can be accomplished.

Even when imperfect patterns or pattern with excess information should be recognized or classified, normalization of the correlation output on the basis of transmission or reflection intensities of patterns to be reviewed and the reference patterns can

improve the performance of recognition of patterns.

The number of the reference patterns to be compared with the pattern to be classified can be drastically reduced by the inventive method.

While the present invention has been described with reference to the particular illustrative embodiments, it is not to be restricted by those embodiments but only the appended claims. It is to be appreciated that those skilled in the art can change or modify the embodiments without departing from the scope and spirit of the present invention.

Claims

1. An optical method of recognition and classification of patterns or image, on real time basis, comprising
 - (a) measuring necessary times a respective output of correlation between each of reference patterns and a specific pattern to be tested which is to belong to a specific class;
 - (b) calculating a representative value for each set of the correlation output, from the set of the measured data of the correlation outputs, in regard to said each of reference patterns and said specific pattern, and a respective parameter to represent the degree of the deviation of the measured data of said correlation outputs belonging to said each set of correlation outputs;
 - (c) making a respective membership function corresponding to each of said reference patterns for each of the specific classes to which the specific pattern should be classified or belong, on the basis of said respective representative value and said respective parameter;
 - (d) estimating a respective membership value to each of the respective membership function, assigned to each of the specific classes to which the pattern should be classified or belong, on the basis of the respective output of correlation between the pattern to be tested and said each of reference patterns;
 - (e) selecting the smallest membership value among the resulting membership values; or estimating an average of all said resulting membership values;
 - (f) using the resulting smallest membership value or the resulting average as a degree to judge how much said pattern to be tested belongs to each of the specific classes.
2. The method of recognition and classification in accordance with claim 1,

wherein said respective correlation output may be a peak value found in a respective range

of an auto-correlation output or cross-correlation output between the pattern to be reviewed and each of the reference patterns.

3. The method of recognition and classification in accordance with claim 1, 5
 wherein said respective output of correlation may be a whole light power or an average light power found in the respective distribution range of an auto-correlation output or cross-correlation output between the pattern to be reviewed and the respective reference pattern. 10
4. The method of recognition and classification in accordance with claim 1, 15
 wherein said respective output of correlation may be a peak value found in a respective range of an auto-correlation output or cross-correlation output between the pattern to be reviewed and the respective reference pattern, and a whole light power or an average light power found in the respective distribution range of said respective auto- or cross- correlation output. 20
5. The method of recognition and classification in accordance with claim 1, 25
 wherein said respective correlation output has been obtained by using a matched filter.
6. The method of recognition and classification in accordance with either one of claims 1 to 4, 30
 wherein said respective correlation output has been obtained by executing separately a jointed Fourier-transformation of the pattern to be reviewed and each of the reference patterns so as to gain each of the intensity patterns, and then Fourier-transforming optically and separately each of the resulting intensity patterns, or alternatively by joint Fourier transforming together the pattern to be reviewed and the respective reference patterns, and then, joint Fourier transforming optically the resulting intensity patterns. 35 40
7. The method of recognition and classification in accordance with claim 1, 45
 wherein said respective correlation output may be a light power of each of the reflection or transmission patterns, which has been obtained by superposing a pattern to be reviewed to each of the respective reference patterns as impressed in term of light transmission distribution and light reflection distribution, and irradiating the resulting superposed one with an incoherent beam so as to form a reflection or transparent light pattern. 50
8. An optical method of recognition and classification of patterns or image, comprising 55

(a) measuring necessary times a respective correlation-output between a specific pattern, and each of reference patterns which is to belong to a specific class;

(b) calculating a representative value for each of the correlation outputs from the each set of the measured data of the correlation outputs in regard to said each of reference patterns and said specific pattern, and a respective parameter to represent the degree of the deviation of the measured data of the correlation outputs;

(c) making a respective first membership function corresponding to each of said reference patterns for each of the specific classes to which the specific pattern should be classified or belong, on the basis of said respective representative value and said respective parameter;

(d) calculating a respective area of the overlapping range of each the first membership function overlapping mutually among said specific classes for the same reference pattern;

or alternatively calculating a maximum membership value in the respective area of the overlapping range of each of the first membership functions mutually overlapping among said specific classes for the same reference pattern;

(e) using said respective area of the overlapping range, or said maximum membership value, as a standard or extent to find how much the mutual specific classes are overlapping each together for the same reference pattern;

(f) determining or selecting a set of the reference patterns with smallest overlapping extent on the basis of said respective area or the minimum membership value;

(g) using said determined set of the reference patterns, to obtain the second membership function corresponding to the determined set of the reference patterns, so that the second membership function is used to obtain a minimum membership value or an average of the membership values in regard to each of the second membership functions corresponding to each of the specific classes,

on the basis of the respective output of the correlation between the pattern to be reviewed and said each pattern of the determined set of the reference patterns;

and

(h) using the obtained minimum membership value or the obtained average of the membership values as a standard to judge the degree as to how much the said pattern to be tested

belongs to each of the specific class into which the said pattern to be tested should be classified.

9. The method of recognition and classification in accordance with claim 8,
 - wherein said determining of the set of the reference patterns, with less overlapping is carried out by
 - (1) estimating the number of the regions, in which the area of the overlapping range of the classes exceeds the predetermined area for each of the reference patterns;
 - (2) choosing a reference pattern with the minimum number of the regions and adding the reference pattern with the smaller number in order from least said numbers, into a set of the reference patterns, producing the new set of reference patterns;
 - (3) counting among all combinations between one specified class and another specified class, the number of the overlapping ranges of the membership functions corresponding to the reference patterns having the larger area than the predetermined area in each pair of the classes;
 - (4) counting the number of the pairs at which the said number of the overlapping ranges is in match to the said number of the reference patterns; and
 - (5) stopping to add the reference patterns, into the set of the reference patterns, and fixing the set of the reference patterns at which the counted number of the pairs is less than the predetermined number.
10. The method of recognition and classification in accordance with claim 8,
 - wherein said determining of the set of the reference patterns, with less overlapping is carried out by
 - (1) calculating the number of the regions in which the maximum membership value in the overlapping range of the classes exceeds the predetermined value for each of the reference patterns;
 - (2) making a set of reference patterns by adding the reference pattern with the minimum number in order from least said number of the regions into a set of the reference patterns, producing the new set of reference patterns;
 - (3) counting among all combinations between one specified class and another specified class, the number of the overlapping ranges of the membership functions corresponding to the reference patterns having the larger area than the predetermined area in each pair of

the classes;

(4) counting the number of the pairs at which the said number of the overlapping ranges is in match to the said number of the reference patterns; and

(5) stopping to add reference patterns into the set of the reference patterns, and fixing the number of the reference patterns in the set at which the counted number of the pairs is less than the predetermined number.

11. The method of recognition and classification in accordance with claim 10,
 - wherein said membership function has a convex curve so that a "fuzzy theory" can be applied, or said function determines convex fuzzy sets.
12. The method of recognition and classification in accordance with claim 8,
 - wherein said respective correlation output may be a peak value found in a respective range of an auto-correlation output or cross-correlation output formed from the pattern to be reviewed and each of the respective reference pattern.
13. The method of recognition and classification in accordance with any one of claim 8 to 11,
 - wherein said respective correlation output may be a whole light power or an average light power found in the respective distribution range of an auto-correlation output or a cross-correlation output formed from the pattern to be reviewed and the respective reference pattern.
14. The method of recognition and classification in accordance with any one of claim 8 to 11,
 - wherein said respective correlation output may be a peak value found in a range of a auto-correlation output or cross-correlation output formed from the pattern to be reviewed and the respective reference pattern, and a whole light power or an average light power found in the distribution range of said auto- or cross-correlation output.
15. The method of recognition and classification in accordance with any one of claim 8 to 14,
 - wherein said correlation output with the respective reference pattern is the output value by itself from the two-dimensional image sensor, or the value obtained by normalization of the output value from the two-dimensional image sensor, on the basis of the transparent light power or the reflection light power from the pattern to be reviewed and two or more reference patterns.
16. The method of recognition and classification in

accordance with any one of claim 8 to 15,
wherein said correlation output with the
respective reference pattern is obtainable in the
range in which the two-dimensional image sensor
has a linearity, or the portion of the correlation
output exceeds the linear region of the light intensity
of said two-dimensional image sensor.

17. The method of recognition and classification in
accordance with any one of claim 8 to 16,
wherein said correlation output with the
respective reference pattern is obtained by using
a filter prepared by using Fourier transform hologram.
18. The method of recognition and classification in
accordance with any one of claim 8 to 16,
wherein said correlation output with the
respective reference pattern is produced by
Fourier transforming respectively and in parallel
the pattern to be reviewed and each of the reference
patterns so as to produce the respective intensity
pattern, and then Fourier transforming
optically and in parallel the resulting respective intensity
pattern,
or alternatively by Fourier transforming respectively
the combinations of the pattern to be reviewed,
and the respective reference pattern,
and then, Fourier transforming optionally and
totally the resulting respective intensity pattern.
19. The method of recognition and classification in
accordance with any one of claim 8 to 16,
wherein said correlation outputs with the
respective reference pattern is a light quantity of
the reflection mode or transparent mode, that is
obtained by superposing a pattern to be reviewed
with the respective reference pattern as indicated
in term of light transparent distribution and light
reflection distribution, and irradiating the resulting
overlayed pattern with an incoherent beam so as
to produce a reflection or transparent beam.

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FIG. 1

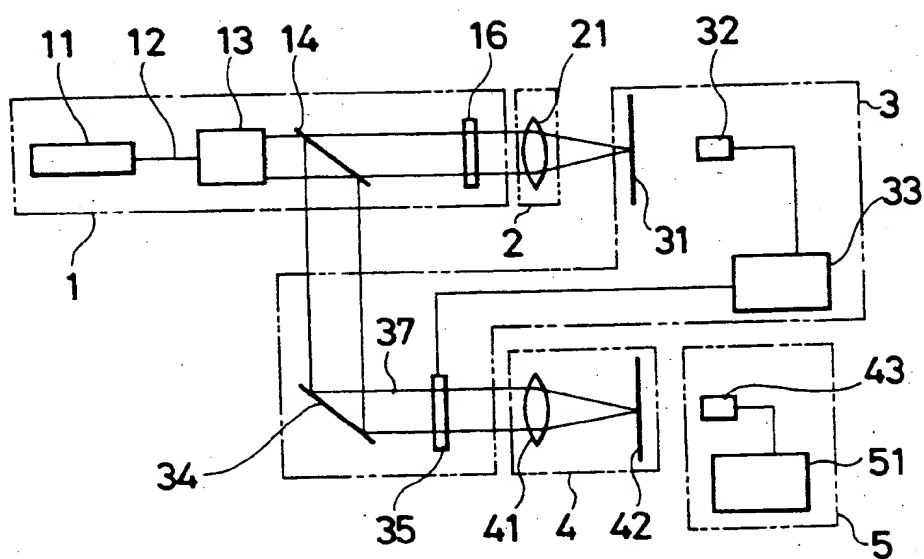


FIG. 2

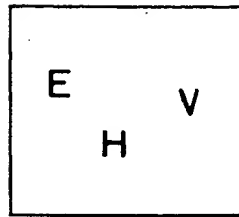


FIG. 3

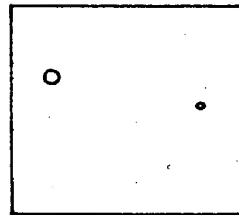


FIG. 4

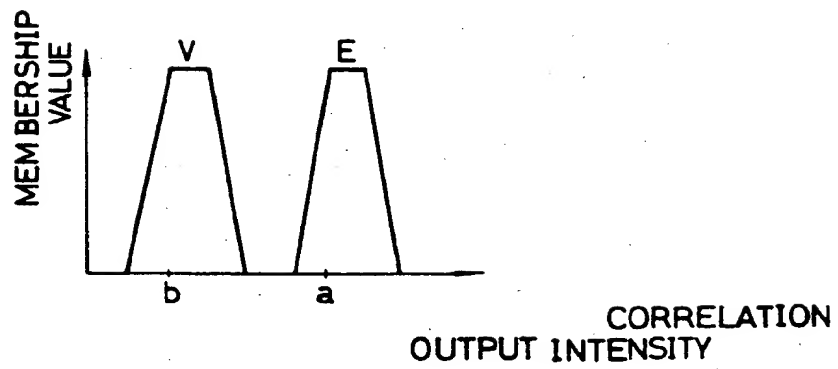


FIG. 5

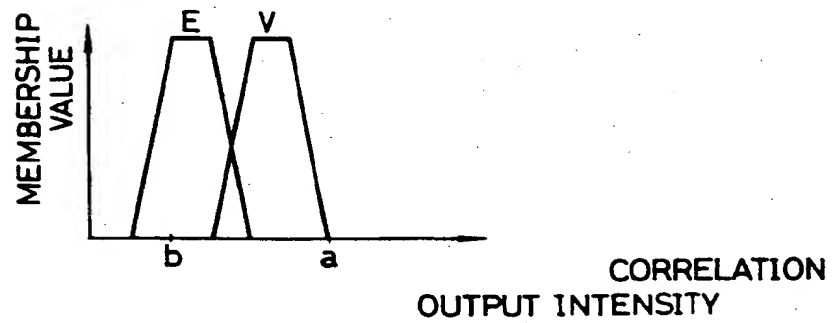


FIG. 6

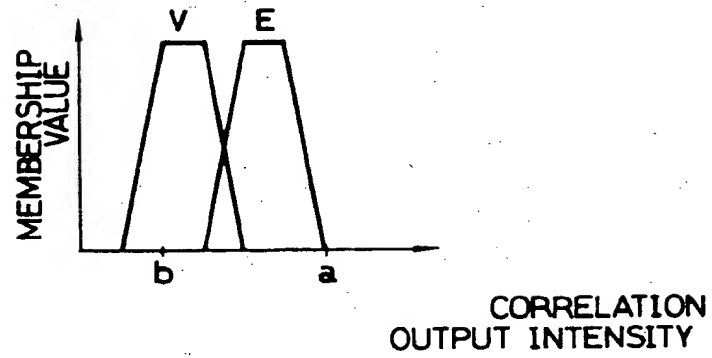


FIG. 7

		MEMBERSHIP VALUE	
		E	V
PATTERN	H	1	1
	N	0	1
	W	0	0
	...		

FIG. 8

(a) $\begin{matrix} E \\ H \end{matrix}$

(b) $\begin{matrix} E \\ H \end{matrix}$

(c) $\begin{matrix} \cdot & \circ \\ & \cdot \end{matrix}$

FIG. 9

MEMBERSHIP FUNCTION

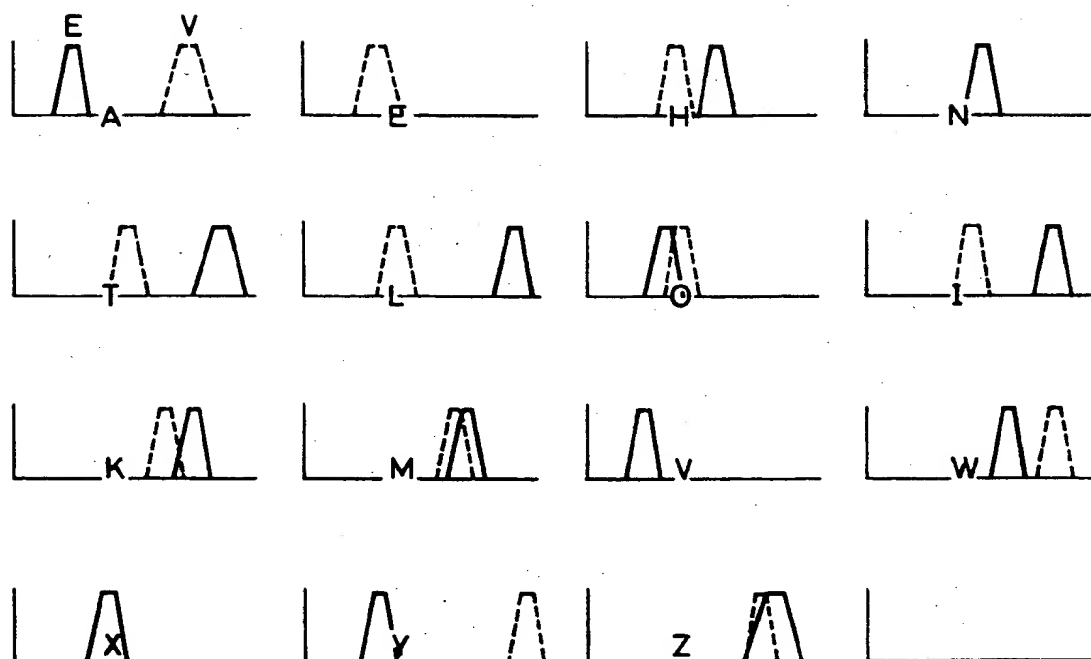


FIG. 10

A (14. 8199)	(44. 3925)	A	100 %		
E (80. 0164)	(19. 1256)	E	100 %		
H (34. 1394)	(24. 8284)	H	100 %		
N (31. 522)	(31. 4905)	N	100 %		
T (53. 7364)	(30. 3136)	T	100 %		
L (55. 4004)	(25. 0414)	T	21. 843 %	L	100%
O (21. 5404)	(23. 9849)	O	100 %		
I (50. 0809)	(26. 449)	T	68. 7639%	L	17. 6659% I 100 %
K (44. 2551)	(37. 1887)	K	100 %	M	64. 8192%
M (41. 7666)	(38. 7179)	K	35. 378%	M	100%
V (14. 7009)	(81. 8856)	V	99. 0819%		
W (36. 0289)	(50. 3511)	W	100 %		
X (22. 8047)	(69. 4826)	X	100 %		
Y (21. 1552)	(56. 2913)	Y	94. 7075%		
Z (46. 0677)	(45. 7495)	Z	100 %		
A (13. 215)	(44. 5128)	A	95. 0843%		
E (75. 7679)	(18. 4227)	E	31. 8977%		
H (34. 8843)	(24. 9244)	H	100%		
N (30. 0191)	(29. 4622)	N	97. 7229%		
T (51. 4392)	(29. 238)	T	100 %	I	59. 5684%
L (53. 1335)	(23. 8895)	L	100 %	I	3. 09244%
O (19. 286)	(24. 5148)	O	100 %		
I (47. 2472)	(28. 3379)	T	31. 782%	I	100%
K (44. 0927)	(37. 9645)	K	100 %	M	70. 2321%
M (41. 0191)	(40. 0013)	K	10. 46%	M	100%
V (13. 9882)	(81. 5805)	V	100 %		
W (35. 7778)	(47. 0888)	W	83. 8287%		
X (22. 5819)	(67. 8074)	X	100 %		
Y (18. 6982)	(57. 0579)	Y	100 %		
Z (46. 2571)	(42. 3353)	K	5. 28399%	Z	56. 1539%
A (14. 9343)	(43. 6095)	A	100 %		
E (76. 2183)	(17. 1847)	E	46. 9098%		
H (34. 2229)	(23. 2564)	H	100 %		
N (29. 0664)	(30. 7548)	N	100 %		
T (51. 3787)	(29. 0986)	T	100 %	I	61. 5845%
L (53. 5556)	(23. 098)	L	100 %		
O (18. 5556)	(23. 597)	O	84. 6132%		
I (45. 213)	(29. 8922)	I	32. 8929%		
K (44. 1078)	(36. 5595)	K	100 %	M	64. 0783%
M (40. 716)	(39. 6279)	K	. 356925%	M	100%
V (14. 0072)	(80. 5141)	V	100 %		
W (35. 261)	(47. 094)	W	84. 0039%		
X (21. 9362)	(70. 4852)	X	100 %		
Y (19. 0861)	(55. 9987)	Y	100 %		
Z (45. 5371)	(44. 9375)	Z	91. 707%		

FIG. 11

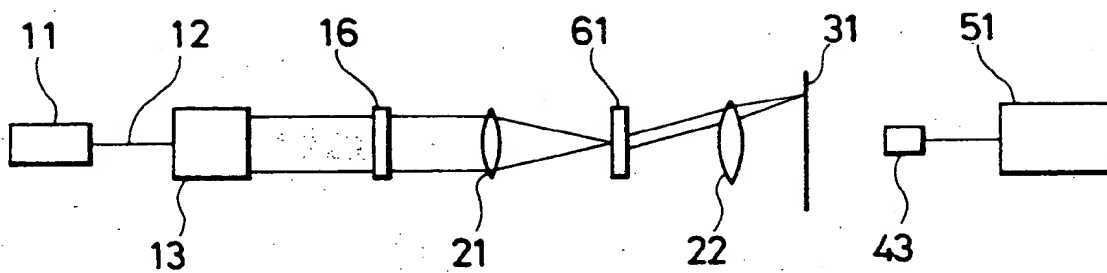


FIG. 12

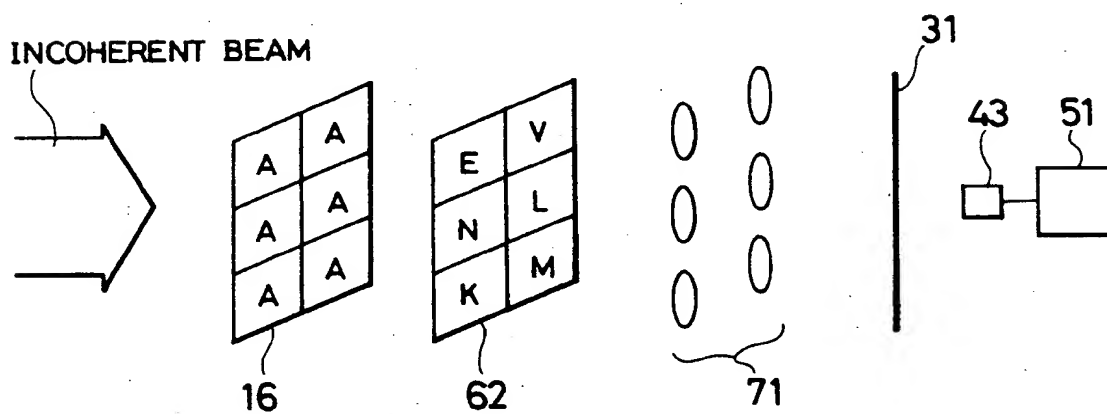


FIG.13

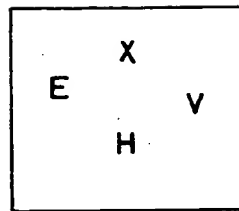


FIG.14

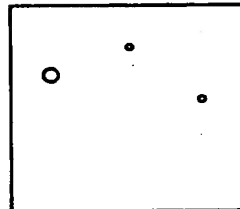


FIG. 15

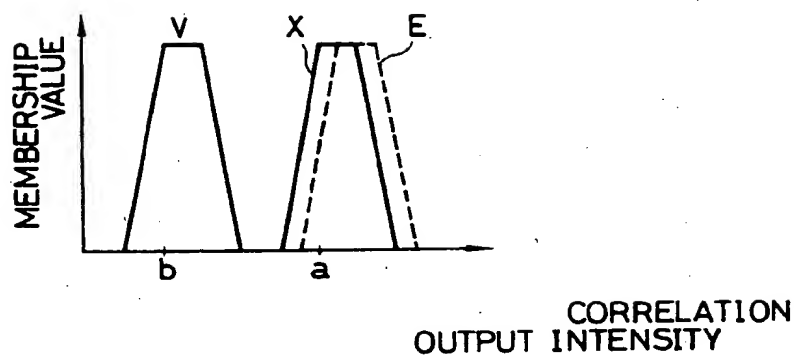


FIG. 16

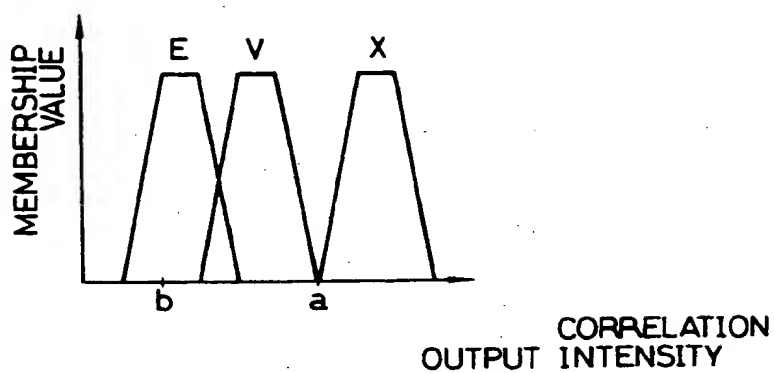


FIG. 17

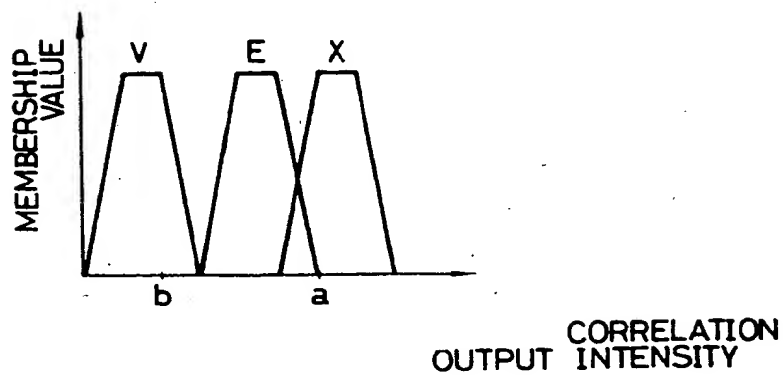


FIG. 18

		OVERLAP AREA OF MEMBERSHIP FUNCTION		
		E	V	X
COMBINATION OF PATTERNS	H-N	0	0.75	0.75
	H-W	0.1	3	6
	N-W	0.75	0	0.75

FIG. 19

		MAXIMUM MEMBERSHIP VALUE IN OVERLAP AREA		
		E	V	X
COMBINATION OF PATTERNS	H-N	0	0.5	1
	H-W	0.2	1	1
	N-W	0.5	0	1

FIG. 20

		NUMBER OF TRANSPOSITION AREAS	
		10	20
NUMBER OF REFERENCE PATTERNS	6	60.67 %	99.22 %
	7	95.13	99.96
	8	99.50	1
	9	99.95	1

FIG. 21

		MEMBERSHIP VALUE	
		E	✓
PATTERN	H	1	1
	N	0	1
	W	0	0
	...		

FIG. 22

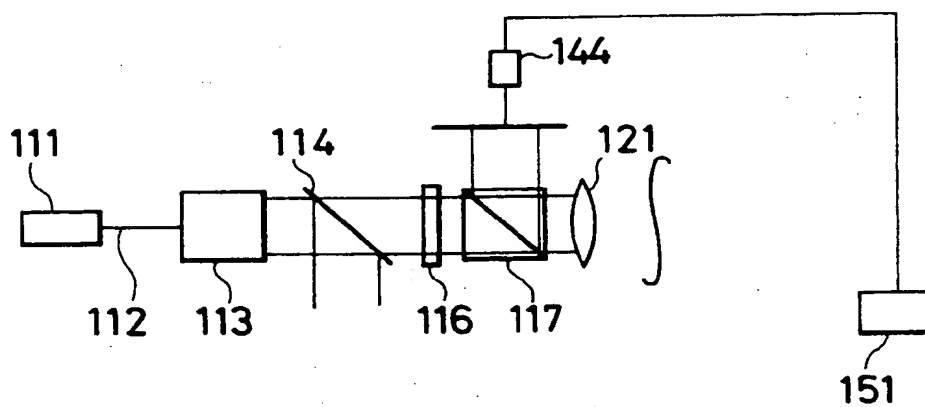
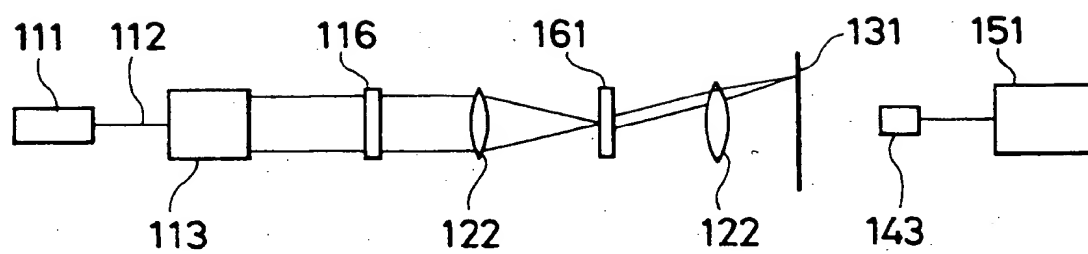


FIG. 23





12 **EUROPEAN PATENT APPLICATION**

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07.03.91 JP 41516/91
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88 Date of deferred publication of search report: **19.01.94 Bulletin 94/03**
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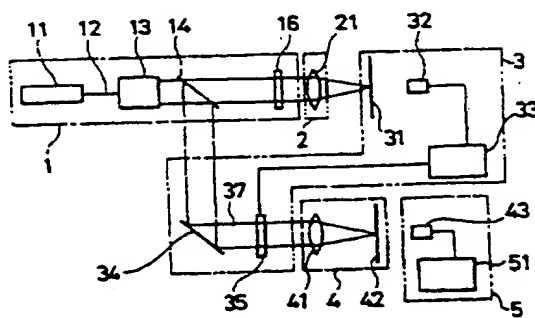
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54 **Method of optical recognition and classification of pattern.**

- 57 1. An optical method of recognition and classification of patterns or image, on real time basis, comprising
- (a) measuring necessary times a respective output of correlation between each of reference patterns and a specific pattern to be tested which is to belong to a specific class;
 - (b) calculating a representative value for each set of the correlation output, from the set of the measured data of the correlation outputs, in regard to said each of reference patterns and said specific pattern, and a respective parameter to represent the degree of the deviation of the measured data of said correlation outputs belonging to said each set of correlation outputs;
 - (c) making a respective membership function corresponding to each of said reference patterns for each of the specific classes to which the specific pattern should be classified or belong, on the basis of said respective representative value and said respective parameter;
 - (d) estimating a respective membership value to each of the respective membership function, assigned to each of the specific classes to which the pattern should be classified or belong, on the basis of the respective output of correlation between the pattern to be tested and said each of reference patterns;
 - (e) selecting the smallest membership value among the resulting membership values;

or estimating an average of all said resulting membership values;
(f) using the resulting smallest membership value or the resulting average as a degree to judge how much said pattern to be tested belongs to each of the specific classes.

FIG. 1



EP 0 500 315 A3



European Patent
Office

EUROPEAN SEARCH REPORT

Application Number
EP 92 30 1315

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int. CL.5)
A	OPTICS COMMUNICATIONS vol. 75, no. 3/4, 1 March 1990, AMSTERDAM NL pages 225 - 30 XP101266 M LIANG ET AL 'Comparison of discrimination capabilities of four types of correlations'	1-19	G06K9/82 G06K9/64 G06K9/68
A	US-A-4 790 024 (N A PEPPERS) 6 December 1988	1-19	
			TECHNICAL FIELDS SEARCHED (Int. CL.5)
			G06K
The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 25 November 1993	Examiner Granger, B
<p>CATEGORY OF CITED DOCUMENTS</p> <p>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</p> <p>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons</p> <p>* : member of the same patent family, corresponding document</p>			

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